INFRASTRUCTURE FOR AVF MODELING

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OVERVIEW

Motivation

- Architectural Vulnerability Factors
 - Program Vulnerability Factor
 - Hardware Vulnerability Factor
 - Spatial Multi-bit Architectural Vulnerability Factor
- ▲ Infrastructure for AVF Measurement
 - Infrastructure Overview
 - API Overview

MOTIVATION MICROPROCESSOR RELIABILITY AND TRANSIENT FAULTS



- Reliability is a major constraint in the design of microprocessors
- ▲ Transient faults are a primary concern in designing reliable microprocessors
 - These faults occur when a particle strike deposits enough charge to flip state in storage elements
- Microprocessor vendors set a failure rate (FIT) target and perform significant analysis to efficiently design for and validate against this target
 - Pre-RTL
 - Architectural Vulnerability Analysis
 - Pre-Silicon
 - Statistical Fault Injection
 - Post-Silicon
 - Particle Beam Testing

Architectural Vulnerability Factors



ARCHITECTURAL VULNERABILITY FACTORS (AVF) [MUKHERJEE03]

- ▲ Not all faults (bit flips) become errors (incorrect program output)
- The Architectural Vulnerability Factor (AVF) of a hardware structure is defined as the probability that a fault in the structure becomes an error
- ▲ AVF can be conservatively estimated through ACE Analysis
 - Determines during each cycle which bits are required for Architecturally Correct Execution (ACE)

$$AVF_{H} = \frac{\sum_{n=0}^{N} ACE \text{ bits in } H \text{ at cycle } n}{B_{H} \times N \qquad B_{H}: \qquad \text{Size in bits}}$$

$$N: \qquad \text{Number of cycles}$$

- Multiple variants of AVF for multiple structures can be estimated during a single faultfree simulation run
- Well suited to early stage (pre-RTL) design exploration
- Much faster than software fault injection

ARCHITECTURAL VULNERABILITY FACTORS CONT.

HARDWARE VULNERABILITY FACTORS AND PROGRAM VULNERABILITY FACTORS [SRIDHARAN09, SRIDHARAN10]

- ▲ Faults which do not propagate into errors are called masked
- ▲ Faults can become masked at many different levels in a system
 - Device level masking
 - Circuit level timing
 - Microarchitecture level masking (Hardware Vulnerability Factor)
 - Register lifetimes
 - Performance enhancing state (branch prediction tables)
 - Architecture level masking (Program Vulnerability Factor)
 - Dynamically dead state
 - Logically masked state
 - Application level masking
 - Approximately correct state
- ▲ AVF considers both microarchitectural and architectural masking
 - AVF = HVF x PVF

ARCHITECTURAL VULNERABILITY FACTORS CONT. SPATIAL MULTI-BIT ARCHITECTURAL VULNERABILITY FACTORS [WILKENING14]

As process technology scales downward it becomes more likely a single particle strike will simultaneously flip multiple bits

- This is known as a spatial multi-bit transient fault
- The effects of spatial multi-bit faults are non-trivial, and spatial multi-bit AVF (MBAVF) can vary significantly from single-bit AVF
- ▲ MBAVF can give insight into reliability behavior involving
 - Various multi-bit patterns (fault modes)
 - Different interleaving schemes and error correcting codes
 - Both microarchitectural and architectural masking



Infrastructure for AVF Measurement



INFRASTRUCTURE FOR AVF MEASUREMENT

AVF Instruction wrapper interfaces with gem5 dynamic instructions Analysis Window performs dataflow analysis on dynamic instruction stream for dynamic deadness and logical masking

Instructions

R/W Events

Reliability

rP

Reliability Structure APIs interface AVF models with gem5 structure models

Reliability Relia Structure Stru

Analysis Window

Reliability Structure

Reliability structures perform lifetime analysis, and model multi-bit modes and protection schemes

INFRASTRUCTURE FOR AVF MEASUREMENT API OVERVIEW

Register committed instructions

 PostCommitBuffer->insert(instruction,

curTick())

// dynamic instruction
// commit cycle

- Register read and write events to modeled state
 - Pass cycle, identifying information for associated instruction, location in modeled structure, and associated architectural state

CPURegisterFile->read_with_association(curTick(), // current cycle device_id, context_id, thread_id, dynamic_id, // instruction identifiers 2, true, 3, // info needed for variable length arguments reg_num, byte, // register #, byte – physical register location thread_id, reg_num, byte) // thread, register #, byte – architectural state

Questions?

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